

# FINAL VERSION

# VERSION FINALE



INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE  
COMITÉ INTERNATIONAL SPÉCIAL DES PERTURBATIONS RADIOÉLECTRIQUES

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**Specification for radio disturbance and immunity measuring apparatus and methods –  
Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements**

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –  
Partie 1-2: Appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques – Dispositifs de couplage pour la mesure des perturbations conduites**

## CONTENTS

FOREWORD.....	7
1 Scope.....	9
2 Normative references .....	9
3 Terms, definitions and abbreviations .....	10
3.1 Terms and definitions.....	10
3.2 Abbreviations.....	12
4 Artificial networks for AC mains and other power ports .....	13
4.1 General.....	13
4.2 AN impedances.....	13
4.3 50 Ω/50 μH + 5 Ω artificial mains V-network (V-AMN) for use in the frequency range 9 kHz to 150 kHz .....	14
4.4 50 Ω/50 μH artificial mains V-network (V-AMN) for use in the frequency range 0,15 MHz to 30 MHz .....	15
4.5 50 Ω/5 μH + 1 Ω artificial mains V-network (V-AMN) for use in the frequency range 150 kHz to 108 MHz .....	16
4.6 (Void).....	18
4.7 150 Ω artificial delta-network (Δ-AN) for mains and other power ports for use in the frequency range 150 kHz to 30 MHz .....	18
4.7.1 Requirements .....	18
4.7.2 Measurement of the Δ-AN parameters .....	19
4.7.3 Current carrying capacity and series voltage drop .....	19
4.8 Isolation.....	20
4.8.1 Requirement.....	20
4.8.2 Measurement procedure.....	20
4.9 Current carrying capacity and series voltage drop.....	21
4.10 Modified reference ground connection .....	21
4.11 Measurement of the voltage division factor of artificial mains V-networks.....	22
5 Current and voltage probes .....	22
5.1 Current probes.....	22
5.1.1 General .....	22
5.1.2 Construction .....	23
5.1.3 Characteristics.....	23
5.2 Voltage probe .....	23
5.2.1 High impedance voltage probe.....	23
5.2.2 Capacitive voltage probe .....	24
6 Coupling units for conducted current immunity measurement .....	27
6.1 General.....	27
6.2 Characteristics.....	27
6.2.1 General .....	27
6.2.2 Impedance.....	27
6.2.3 Insertion loss .....	27
7 Coupling devices for measuring signal lines .....	28
7.1 General.....	28
7.2 Requirements for AANs (or Y-networks).....	28
7.3 Requirements for artificial networks for coaxial and other screened cables.....	32

8	The artificial hand and series RC element .....	32
8.1	General.....	32
8.2	Construction of the artificial hand and RC element.....	32
8.3	The use of the artificial hand.....	33
9	CDNE for measurement of disturbance voltage in frequency range 30 MHz to 300 MHz.....	36
9.1	Instrumentation.....	36
9.1.1	General .....	36
9.1.2	Description of the CDNE measurement.....	37
9.1.3	Description of the RGP .....	37
9.2	Technical requirements for the CDNE-X.....	38
9.2.1	Mechanical and electrical parameters .....	38
9.2.2	Validation of the CDNE .....	38
9.3	Technical requirement for the RGP .....	41
	Annex A (normative) Characteristics and their measurement, circuit schemes and examples of modern implementations of AMNs and other ANs for use with power or load ports of EUTs.....	42
A.1	General.....	42
A.2	An example of the 50 $\Omega$ /50 $\mu$ H + 5 $\Omega$ artificial mains V-network.....	42
A.3	An example of the 50 $\Omega$ /50 $\mu$ H artificial mains V-network .....	43
A.4	Examples of the 50 $\Omega$ /5 $\mu$ H + 1 $\Omega$ artificial mains V-network.....	43
A.5	(Void).....	44
A.6	Examples of the 150 $\Omega$ $\Delta$ -AN .....	44
A.7	Example design for an AMN with a 50 $\mu$ H inductor .....	47
A.7.1	The inductor .....	47
A.7.2	The case of the inductor .....	48
A.7.3	Isolation of the inductor .....	49
A.8	Measurement of the voltage division factor of an artificial mains V-network .....	49
	Annex B (informative) Construction, frequency range, and calibration of current probes .....	52
B.1	Physical and electrical considerations for current probes .....	52
B.2	Equivalent electrical circuit of current probe.....	54
B.3	Detrimental effects of current probe measurements .....	54
B.4	Typical frequency response characteristics of current probes.....	55
B.5	A shielding structure for use with current probes.....	56
B.5.1	General .....	56
B.5.2	Theoretical model.....	57
B.5.3	Construction of the shielding structure.....	58
B.5.4	High-pass filter .....	58
B.6	Calibration of current probes.....	58
	Annex C (informative) Construction of the coupling units for current injection for the frequency range 0,15 MHz to 30 MHz .....	62
C.1	Coupling unit type A for coaxial antenna input .....	62
C.2	Coupling unit type M, for mains leads .....	62
C.3	Coupling unit type L, for loudspeaker leads.....	65
C.4	Coupling unit type Sw, for audio-frequency signals .....	66
C.5	Coupling unit type Sw, for audio, video, and control signals .....	66
	Annex D (informative) Principle of operation and examples of coupling units for conducted current immunity measurements .....	68

D.1	Principle of operation .....	68
D.2	Types of unit and their construction .....	68
Annex E (normative) Example and measurement of the parameters of the asymmetric artificial network (AAN) .....		72
E.1	Description of an example of an AAN: the T-network.....	72
E.2	Measurements of the parameters of an asymmetric artificial network (AAN) .....	72
Annex F (normative) Example and measurement of the parameters of the AN for coaxial and other screened cables .....		78
F.1	Description of ANs for coaxial and other screened cables .....	78
F.2	Measurements of parameters of an AN for coaxial and other screened cables .....	78
Annex G (informative) Construction and evaluation of capacitive voltage probe .....		80
G.1	General.....	80
G.2	Physical and electrical considerations for CVP.....	80
G.3	Determination of the frequency response of the voltage division factor .....	80
G.4	Method of measurement to determine the influence of external electric fields.....	81
G.4.1	Influence of external electric field .....	81
G.4.2	Method of measurement to determine the influence of the external electric field .....	81
G.5	Pulse response .....	81
G.6	Voltage division factor dependence.....	82
Annex J (informative) Example CDNE set-up diagrams .....		90
J.1	CDNE-M2 and CDNE-M3 .....	90
J.2	CDNE-S <sub>x</sub> .....	92
Annex K (normative) Measurement of Δ-AN parameters .....		93
Annex I (informative) Rationale for the introduction of a phase tolerance for the V-AMN input impedance .....		88
Annex H (informative) Rationale for the introduction of a minimum decoupling factor between mains and EUT/receiver ports for the V-AMN.....		87
Bibliography.....		95
Figure 1 – Impedance (magnitude and phase) of the V-network for Band A (see 4.3, the relevant frequency range is from 9 kHz to 150 kHz) .....		17
Figure 2 – Impedance (magnitude and phase) of the V-network for Band B (see 4.4).....		17
Figure 3 – Impedance (magnitude and phase) of the V-network for Bands B and C (from 150 kHz to 108 MHz; see 4.5).....		18
Figure 5 – Example of artificial mains 50 Ω/50 μH + 5 Ω V-network (see 4.3 and A.2).....		21
Figure 6 – Example of artificial mains V-networks, 50 Ω/50 μH, 50 Ω /5 μH + 1 Ω or 150 Ω (see 4.4, 4.5, 4.6, A.3, A.4 and A.5, respectively) .....		22
Figure 7 – Circuit for RF voltage measurement on supply mains .....		24
Figure 8 – Circuit used to make voltage measurements between a cable and reference ground .....		26
Figure 9 – Measuring set-up to check the insertion loss of the coupling units in the frequency range 30 MHz to 150 MHz .....		27
Figure 10 – Principal circuit and LCL requirements of an AAN .....		30
Figure 11 – Application of the artificial hand .....		35
Figure 12 – Examples of application of artificial hand to ITE .....		36

Figure 13 – Arrangement for validation of a CDNE.....	39
Figure 14 – IMA arrangement for correcting the electrical length.....	40
Figure 15 – Test arrangement for the measurement of the symmetric impedance ( $Z_{DM}$ ).....	41
Figure A.1 – Example of an alternative 50 $\Omega$ /5 $\mu$ H + 1 $\Omega$ V-AMN for devices used with low impedance power sources .....	44
Figure A.2 – Example of a 150 $\Omega$ $\Delta$ -AN for low current drain across the AN for the measurement of asymmetric and symmetric disturbance voltages.....	45
Figure A.3 – Schematic of 50 $\mu$ H inductor .....	48
Figure A.4 – General view of an AMN .....	48
Figure A.5 – Attenuation of an AMN filter .....	49
Figure A.6 – Test set-up for determining the voltage division factor .....	50
Figure A.7 – Example of a 150 $\Omega$ $\Delta$ -AN for high current drain across the AN for the measurement of asymmetric and symmetric disturbance voltages.....	47
Figure B.1 – Typical current probe configuration .....	53
Figure B.2 – High-pass filter with cut-off frequency of 9 kHz .....	55
Figure B.3 – Transfer impedance of typical current probes.....	56
Figure B.4 – Set-up for current measurement using the AMN .....	57
Figure B.5 – Shield configuration used with current transformer.....	58
Figure B.6 – Schematic diagram of circuit with coaxial adaptor and current probe transfer admittance $Y_T$ measurement.....	59
Figure B.7 – Transfer admittance $Y_T$ as a function of frequency.....	60
Figure B.8 – Return loss of the coaxial adaptor terminated with 50 $\Omega$ and with the current probe (also terminated with 50 $\Omega$ ) inside .....	60
Figure B.9 – Current probe between the two halves of the coaxial adaptor.....	61
Figure C.1 – Example of coupling unit type A, for coaxial input schematic diagram and construction details (see C.1 and D.2) .....	63
Figure C.2 – Example of coupling unit type M, for mains leads, schematic diagram and construction details (see C.2 and D.2) .....	64
Figure C.3 – Example of coupling unit type L for loudspeaker leads, schematic diagram and simplified construction drawing (see D.2) .....	65
Figure C.4 – Example of coupling unit type Sw, for audio signals. Schematic diagram and simplified construction drawing (see D.2) .....	66
Figure C.5 – Example of coupling unit type Sw, for audio, video and control signals, schematic diagram and simplified construction drawing (see D.2) .....	67
Figure D.1 – General principle of the current-injection method (see D.1).....	70
Figure D.2 – Coupling unit type Sr with load resistances – Schematic diagram and simplified construction drawing (see D.2).....	71
Figure E.1 – Example of a T-network circuit for one pair of wires .....	73
Figure E.2 – Arrangement for the termination impedance measurement.....	74
Figure E.3 – Arrangement for LCL probe verification.....	74
Figure E.4 – Arrangement for the LCL probe calibration using an L-circuit .....	75
Figure E.5 – LCL measurement of the AAN using an LCL probe .....	75
Figure E.6 – Test set-up for the decoupling attenuation (isolation) of the AAN	
$a_{\text{decoup}} = 20 \lg \left  \frac{V_1}{V_2} \right  - a_{\text{vdiv}}$ in dB for asymmetric signals between AE port and EUT port .....	76
Figure E.7 – Test set-up for the insertion loss (symmetric) of the AAN.....	76

Figure E.8 – Calibration test set-up for the AAN voltage division factor of the asymmetric circuit:  $F_{\text{AAN}} = a_{\text{vdiv}} = 20\lg\left|\frac{V_1}{V_2}\right|$  in dB ..... 77

Figure F.1 – Example of a coaxial cable AN..... 78

Figure F.2 – Test set-up for the coaxial and screened cable AN voltage division factor  $F_{\text{AN}} = 20\lg\left|\frac{V_1}{V_2}\right|$  in dB..... 79

Figure G.1 – Configuration of a CVP ..... 83

Figure G.2 – Equivalent circuit of a CVP ..... 84

Figure G.3 – Test set-up to measure the frequency response ..... 84

Figure G.4 – Electrostatic coupling model and its equivalent circuit ..... 85

Figure G.5 – Test set-up to measure the reduction, through the shielding effect, of the influence of the external electric field caused by electrostatic coupling ..... 85

Figure G.6 – Conversion factor deviation when cable position is changed..... 86

Figure G.7 – Investigation result of the cable radius dependence..... 86

Figure H.1 – Isolation measurement arrangement..... 87

Figure I.1 – Definition of impedance magnitude and phase tolerances ..... 88

Figure J.1 – CDNE-M3 with internal attenuator  $a_{\text{meas}}$  of at least 6 dB..... 90

Figure J.2 – CDNE-M2 with internal attenuator  $a_{\text{meas}}$  of at least 6 dB..... 91

Figure J.3 – CDNE-S<sub>x</sub> for screened cable with  $x$  internal wires and an internal attenuator of at least 6 dB..... 92

Figure K.1 – Calibration of the set-up with an open, short and match (50 Ω) standard reference termination ..... 93

Figure K.2 – Set-up for the measurement of the symmetric impedance ..... 93

Figure K.3 – Set-up for test system normalization ..... 94

Figure K.4 – Set-up for symmetric voltage division factor measurement..... 94

Figure K.5 – Set-up for the measurement of the insertion loss of a balun by measuring the insertion loss of two identical baluns..... 94

  

Table 1 – Magnitudes and phase angles of the V-network (see Figure 1)..... 14

Table 2 – Magnitudes and phase angles of the V-network (see Figure 2)..... 15

Table 3 – Magnitudes and phase angles of the V-network (see Figure 3)..... 16

Table 4 – Values of minimum isolation for V-networks ..... 20

Table 5 – Characteristics of the AAN for the measurement of asymmetric disturbance voltage..... 31

Table 6 – Characteristics of artificial networks for coaxial and other screened cables ..... 32

Table 7 – Electrical parameters of the CDNE-X..... 38

Table 8 – Parameters of the 150 Ω Δ-AN (150 kHz to 30 MHz) ..... 19

Table 9 – Parameters of the 150 Ω Δ-AN (9 kHz to 150 kHz) ..... 19

Table A.1 – Component values of 50 Ω/50 μH + 5 Ω V-network ..... 42

Table A.2 – Component values of 50 Ω/50 μH V-network ..... 43

Table A.3 – Component values of 50 Ω/5 μH + 1 Ω V-network ..... 44

Table A.4 – Component values of the 150 Ω Δ-AN shown in Figure A.2..... 46

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INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

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**SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY  
MEASURING APPARATUS AND METHODS –**

**Part 1-2: Radio disturbance and immunity measuring apparatus –  
Coupling devices for conducted disturbance measurements**

**FOREWORD**

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**This Consolidated version of CISPR 16-1-2 bears the edition number 2.1. It consists of the second edition (2014-03) [documents CISPR/A/1051/FDIS and CISPR/A/1059/RVD] and its amendment 1 (2017-11) [documents CIS/A/1222/FDIS and CIS/A/1232/RVD]. The technical content is identical to the base edition and its amendment.**

**This Final version does not show where the technical content is modified by amendment 1. A separate Redline version with all changes highlighted is available in this publication.**

International Standard CISPR 16-1-2 has been prepared by subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

This second edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) requirements from CISPR 22 for the AAN have been copied to this standard;
- b) the CDNE for measurement of disturbance voltage in the frequency range 30 MHz to 300 MHz is added;
- c) additional maintenance is included.

It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

A list of all parts of CISPR 16 series, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods*, can be found on the IEC website.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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## **SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –**

### **Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements**

#### **1 Scope**

This part of the CISPR 16 series specifies the characteristics and performance of equipment for the measurement of radio disturbance voltages and currents in the frequency range 9 kHz to 1 GHz.

NOTE In accordance with IEC Guide 107, CISPR 16 is a basic EMC standard for use by product committees of the IEC. As stated in Guide 107, product committees are responsible for determining the applicability of the EMC standard. CISPR and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular EMC tests for specific products.

Specifications for ancillary apparatus are included for artificial mains networks, current and voltage probes and coupling units for current injection on cables.

It is intended that the requirements of this publication are fulfilled at all frequencies and for all levels of radio disturbance voltages and currents within the CISPR indicating range of the measuring equipment.

Methods of measurement are covered in the CISPR 16-2 series, and further information on radio disturbance is given in CISPR 16-3, while uncertainties, statistics and limit modelling are covered in the CISPR 16-4 series.

#### **2 Normative references**

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1-1:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-2-1:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements*

CISPR 16-4-2:2011, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Measurement instrumentation uncertainty*

IEC 60050 (all parts), *International Electrotechnical Vocabulary* (available at <<http://www.electropedia.org>>)

IEC 61000-4-6:2008, *Electromagnetic compatibility (EMC) – Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields*